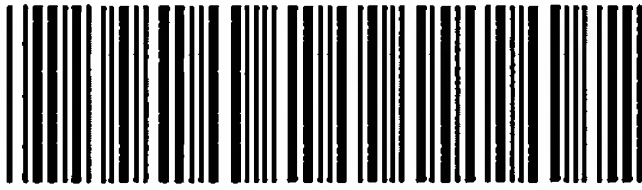


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/609,496	LEE ET AL.	
	Examiner	Art Unit	
	Jia W. Lu	2611	

SEARCHED			
Class	Subclass	Date	Examiner
375	316	9/7/2006	JL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
375	316	9/7/2006	JL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
ALL EAST DATABASES	9/7/2006	JL
INVENTORSHIP	9/7/2006	JL